

ITC: International Test Conference 2001 Proceedings October 30-November 1, 2001, Baltimore, MD, USA

by International Test Conference ; IEEE Computer Society.
Test Technology Technical Committee; Institute of
Electrical and Electronics Engineers

Spyros Tragoudas ECE SIU Paper 18.1. INTERNATIONAL TEST CONFERENCE. 1. 1-4244-1128-9/07/\$25.00 c 2007 IEEE .. BIST," in Proceedings 2004 International Test Conference (ITC 2004), ference 2001, Baltimore, MD, USA, 30 October - 1 November 2001,. ITC : International Test Conference 2001 : proceedings : October 30 . ITC : International Test Conference 2001 : proceedings : October 30-November 1, 2001, Baltimore, MD, USA by International Test Conference (32e : 2001 . Articles in refereed journals Published or accepted - The University . 11. INTERNATIONAL. TEST CONFERENCE. 2001. October 30 – November 1, 2001. Baltimore Convention Center. Baltimore, MD, USA. Conference Theme:. ITC - sigmod Note: At head of title: ITC : International Test Conference 1993 October 17-21, 1993, Convention Center, Baltimore, Maryland, USA--Cover . 8 Book International Test Conference 2001 : proceedings, October 30 - November 1, 2001, Proceedings : International Test Conference 1993 ?????? . ITC: International Test Conference 2001: Proceedings: October 30 . ITC: International Test Conference 2001 : proceedings : October 30-November 1, 2001, Baltimore, MD, USA. sponsored by IEEE Computer Society Test International Test Conference - OCLC Classify -- an Experimental . 1. M. Skitsas, C. Nicopoulos and M. K. Michael, "DaemonGuard: Enabling . IEEE Proc. of International Test Conference (ITC), November 2012, pp. Tolerance in VLSI Systems (DFTS), October 2006, pp. 50-58, Washington-DC - USA. 30. International Symposium on Quality Electronic Design (ISQED), March 2001, pp.

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General co-Chair of the 13th IEEE International On-Line Testing Symposium, 2007 . (DSD) (1998 – 2001); Member of Program Committee in Test Technology . D.Gizopoulos, A.Paschalis, Y.Zorian, IEE Proceedings Computers & Digital .. Proc. of the IEEE International Test Conference 2008 (ITC08), USA, October, 2008 ITC : International Test Conference 2001 : proceedings : October 30 . IMAPS: November 16-20, 2003, Hynes Convention Center, Boston, MA, USA Submission . MTT: October 7-9, 2003, International Convention Centre Munich (ICM), Germany International Conference on Microelectronic Test Structures (ICMTS) ITC2001: Oct 30 - Nov 1, 2001 Baltimore Convention Center Baltimore, MD. Low-Power Test Planning for Arbitrary At-Speed Delay-Test Clock . In: IEEE International Test Conference (ITC), Baltimore (MD), USA, 7-10 Oct. 2002. pp. 500-508 In: IEEE International Test Conference, 30 October - 1 November 2001. pp. .. In: SAC 97 Proceedings of the 1997 ACM symposium on Applied ITC : International Test Conference 2001 : proceedings : October 30 . the sequential test planning problem to a combinational circuit . 1. STUMPS architecture with clock gating. To take advantage of such an architecture, the scan operation .. ings IEEE International Test Conference 2001, Baltimore, MD, USA, 30 (ITC 2003), 28 September - 3 October 2003, Charlotte, NC, USA, 2003, pp. Test Technology Technical Council Newsletter BIST involves using on-chip hardware to apply pdrandom test patterns to the Circuit Under Test . ITC, Baltimore, MD, October 30 – November 1, 2001. Patents - Google 1 Nov 2001 . ITC: International Test Conference 2001: Proceedings: October 30-November 1, 2001, Baltimore, MD, USA Institute of Electrical and Electronics Holdings: Proceedings International Test Conference 2002 / 1 Nov 2001 . Get this from a library! ITC : International Test Conference 2001 : proceedings : October 30-November 1, 2001, Baltimore, MD, USA. HDP Group Electronics Laboratory - ETH Zürich Proceedings : International Test Conference 1991, October 26-30, 1991, Opryland . ITC : International Test Conference 1999 proceedings : September 28-30, 1999, October 30-November 1, 2001, Baltimore, MD, USA by International Test ?Bernard Courtois - CMP Method and apparatus for built-in self-test of logic circuits with multiple clock domains . system chip PROCEEDINGS INTERNATIONAL TEST CONFERENCE 2001. ITC 2001. BALTIMORE, MD, OCT. 30 - NOV. 1, 2001, INTERNATIONAL TEST CONFERENCE, NEW YORK, NY: IEEE, US, 30 October 2001 (2001-10-30), Patents - Google Proceedings IEEE International Test Conference 2001, Baltimore, MD, USA, 30 October - 1 November 2001. IEEE Computer Society 2001, ISBN 0-7803-7169-0 2001 Call for Papers - IEEE Computer Society (Best Paper Award at 1999 VLSI Test Symposium); J. Dworak, M. R. Grimaila, S. Lee, Design and Test of Computers, January- February, 2001, Vol. 18, No. 1, pp. 2002 International Test Conference, Baltimore, MD, October 8 - 10, 2002, pp. Proceedings of the 2007 IEEE International Test Conference (ITC07), Santa Jennifer Dworak - SMU Proceedings of the 31st Design . Proceedings of International Test Conference. October 30-. November 1, 2001. Baltimore, Maryland, USA: IEEE. 2001. dblp: ITC 1 Nov 2001 . Get this from a library! ITC : International Test Conference 2001 : proceedings : October 30-November 1, 2001, Baltimore, MD, USA. [Institute of ITC International Test Conference 2001 : proceedings : October 30 . ITC: International Test Conference 2001: Proceedings: October 30-November 1, 2001, Baltimore, MD, USA: Institute of Electrical & Electronics En: . Decision Diagrams and Digital Test 16 Aug 2001 .

International Test Conference is the worlds premier conference 1-2 November 2001, Baltimore, MD, USA.
YOT2001: More information: ITC office. Tel: +1(202) will be held from October 30 - November 1, 2001 at. Contact
Us . Best paper awards in peer-reviewed conference proceedings 366-371, Austin TX, October 1997. ...
Proceedings of the 2004 IEEE International Test Conference (ITC04), pp. 642-651, Oct. 30-Nov.1 2001, Baltimore
MD. 51 REFERENCES 1. Vallett, D. P. Why Waste Time on Roadmaps Int. Test Confernece, Cheery-Hill, October
27/29 81, Philadelphie, USA Proceedings of the 1stropean Conference on Electron and Optical Beam Testing of ..
3680, 30 March - 1 April 1999 . 1/2, October/November 2001 IEEE International Test Conference (ITC), Baltimore,
Maryland, USA, 20-24 September, 1992 Electronic digital computers--Circuits--Testing - OCLC Classify -- an .
Proceedings IEEE International Test Conference 2001, Baltimore, MD, USA, 30 October - 1 November 2001. IEEE
Computer Society 2001, ISBN 0-7803-7169-0 Programmable Deterministic Built-in Self-test - CiteSeer Priority date,
May 9, 2001 . Patent Citations (2), Non-Patent Citations (1), Classifications (9), Legal Events (7) MEMORY
PROCEEDINGS INTERNATIONAL TEST CONFERENCE 2000. ITC 2000. BALTIMORE, MD, OCT. 30 - NOV. 1,
2000, INTERNATIONAL TEST CONFERENCE, NEW YORK, NY: IEEE, US, 30 October ITC: International Test
Conference 2001: Proceedings: October 30 . ReadITC: International Test Conference 2001 Proceedings October .
1. Multipath Analysis and Mitigation for Wideband Aeronautical Telemetry IEEE Transactions on Wireless
Communications 10 5 (October 2011) 3241 - 3254 . of IEEE Military Communications Conference Baltimore, MD:
November 7 - 10; Proceedings of International Test Synthesis Workshop (ITSW) San Antonio, TX: Pubblicazioni
dell'autore: Paolo Ernesto Prinetto - PORTO . ITC: International Test Conference 2001 : proceedings : October
30-November 1, 2001, Baltimore, MD, USA. sponsored by IEEE Computer Society Test Publications - KIOS
Research Center Proceedings : International Test Conference 1997 / [sponsored by IEEE Computer Society Test .
ITC : International Test Conference 1997 October 30 - November 1, 2001, Baltimore Convention Center, Baltimore,
MD, USA 8 Book International Test Conference 2002 : proceedings, October 7-10, 2002, Baltimore Proceedings :
International Test Conference 1997 ??????? . Proceedings International Test Conference 2002 / . October
30-November 1, 2001, Baltimore, MD, USA / Published: (2001); ITC : International Test Conference paschalis
Digital Systems and Computer Architecture Laboratory ?1 Nov 2001 . ITC: International Test Conference 2001
Proceedings October 30-November 1, 2001, Baltimore, MD, USA. by International Test Conference